

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re: Franzen et al. Serial No.: 10/669,401 Filed: September 23, 2003 Group Art Unit: 2878
Examiner: To Be Assigned
Confirmation No.: 3963

For:

SURFACE PLASMON RESONANCE SYSTEMS AND METHODS HAVING A

VARIABLE CHARGE DENSITY LAYER

Date: February 24, 2004

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

## INFORMATION DISCLOSURE STATEMENT UNDER 37 C.F.R. § 1.97(b)

Sir:

Attached is a list of documents on Form PTO-1449, together with a copy of any listed foreign patent document and/or non-patent literature. A copy of any listed U.S. patent and/or U.S. patent application publication is not provided herewith in accordance with the waiver by the U.S. Patent and Trademark Office of requirements under 37 C.F.R. § 1.98(a)(2)(i) for all U.S. national patent applications filed after June 30, 2003 and for all international applications that have entered the national stage under 35 USC § 371 after June 30, 2003.

It is requested that these documents be considered by the Examiner and officially made of record in accordance with the provisions of 37 C.F.R. § 1.56 and Section 609 of the MPEP.

No fee is believed due. However, the Commissioner is hereby authorized to charge any deficiency or credit any overpayment to Deposit Account No. 50-0220.

Respectfully submitted,

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I hereby certify that this correspondence is being deposited with the United States Postal Service with sufficient postage as first class mail in an envelope addressed to: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 223 13-1450 on February 24, 2004.

Carey Gregory /

FORM PTO		U.S. Department on the and Trademark (		Attorney Docket Number 5051-606			Serial No. 10/669,401			
LIST 8 2 6 2004	M	OCUMENTS CITE se several sheets if		CANT						
PRADENABIS					Applicants: Franzen et al.					
					Filing Date: September 23, 2003			Group 2878		
	<del></del>	U. S. P.	ATENTS & P	PATENT APPL	ICATION PUBI	LICATIONS		<u> </u>		
Examiner Initial		Document Number	Date	Name		Class	Subclass	Filing Date if Appropriate		
	1.	6,143,574	11/7/00	Karlsson et al		436	517			
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	5.	5,641,640	6/24/97	Hanning		435	7.92			
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	<ul> <li>Brewer, S; Brown, D; Franzen, S; "Formation of Thiolate and Phosphonate Adlayers on Indium-tin Oxide: Optical and Electronic Characterization" Langmuir 2002, 18, 6857-6865.</li> <li>Allara, D.; Nuzzo, 1985, 1, 45-52.</li> </ul>								
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